

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/576,187 | | Applicant(s)/Patent Under Reexamination BAIONI ET AL. | |
| | Examiner CHRISTOPHER C. CAILLOUET | | Art Unit 1791 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-4,670,081 A | 06-1987 | Takahashi et al. | 156/384 |
| * | B | US-4,795,414 A | 01-1989 | Blumle, Martin | 493/403 |
| * | C | US-5,196,083 A | 03-1993 | Baker et al. | 156/364 |
| * | D | US-5,417,383 A | 05-1995 | Rodriguez et al. | 242/526.2 |
| * | E | US-5,776,285 A | 07-1998 | Blumle, Martin | 156/256 |
| * | F | US-6,146,728 A | 11-2000 | Bay, Christian | 428/40.1 |
| * | G | US-6,572,520 B2 | 06-2003 | Blumle, Martin | 493/450 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | I | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.